

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier	User Part Number					
Nexperia B.V.	IP4234CZ6					
Name of Laboratory	Part Description					
	Nexperia DHAM Protection Bipolar					
Assembly reliability labs	SMD package					
Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects	
TEST Pre- and Post-Stress						
# 1 Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
PC # 2 Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	286	21480	0	
HTRB High Temperature Reverse # 5 Bias	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	23	1840	0	
TC # 7 Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	86	6880	0	
AC # 8 Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	86	6880	0	
H3TRB High Humidity High # 9 Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage $^{[1]}$	1000 hours	86	6880	0	
# 10 Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj = 100$ °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.	
RSH # 20 Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	28	840	0	
SD # 21 Solderability	J-STD-002		36	360	0	

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Protection Bipolar	1840	0	2.31	4.33E+08

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